

Data Sheet January 2000 File Number 3741.2

# 50A, 1200V Ultrafast Diode

The RURU50120 is an ultrafast diode with soft recovery characteristics ( $t_{rr}$  < 125ns). It has low forward voltage drop and is of silicon nitride passivated ion-implanted epitaxial planar construction.

This device is intended for use as a freewheeling/clamping diode and rectifier in a variety of switching power supplies and other power switching applications. Its low stored charge and ultrafast soft recovery minimize ringing and electrical noise in many power switching circuits, thus reducing power loss in the switching transistors.

Formerly developmental type TA49099.

## **Ordering Information**

PART NUMBER	PACKAGE	BRAND
RURU50120	TO-218	RURU50120

NOTE: When ordering, use the entire part number.

## Symbol



#### **Features**

Ultrafast with Soft Recovery	
Operating Temperature	175 <sup>0</sup> C
Reverse Voltage	1200V

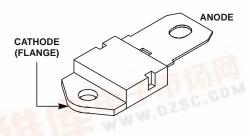
- Avalanche Energy Rated
- · Planar Construction

### **Applications**

- · Switching Power Supplies
- Power Switching Circuits
- General Purpose

### **Packaging**

**SINGLE LEAD JEDEC STYLE TO-218** 



#### **Absolute Maximum Ratings** T<sub>C</sub> = 25°C, Unless Otherwise Specified

	RURU50120	UNITS
Peak Repetitive Reverse VoltageVRRM	1200	V
Working Peak Reverse Voltage	1200	V
DC Blocking VoltageV <sub>R</sub>	1200	COMV
Average Rectified Forward Current $I_{F(AV)}$ ( $T_C = 85^{\circ}C$ )	50	Α
Repetitive Peak Surge Current	100	Α
Nonrepetitive Peak Surge Current	500	Α
Maximum Power Dissipation	170	W
Avalanche Energy (See Figures 10 and 11)	50	mJ
Operating and Storage Temperature	-65 to 175	°С



 $\textbf{Electrical Specifications} \hspace{0.5cm} \textbf{T}_{C} = 25^{o}\text{C}, \hspace{0.1cm} \textbf{Unless Otherwise Specified}$ 

SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNITS
V <sub>F</sub>	I <sub>F</sub> = 50A	-	-	2.1	V
	I <sub>F</sub> = 50A, T <sub>C</sub> = 150 <sup>o</sup> C	-	-	1.9	V
I <sub>R</sub>	V <sub>R</sub> = 1200V	-	-	250	μА
	$V_R = 1200V, T_C = 150^{\circ}C$	-	-	2.0	mA
t <sub>rr</sub>	$I_F = 1A$ , $dI_F/dt = 100A/\mu s$	-	-	125	ns
	$I_F = 50A$ , $dI_F/dt = 100A/\mu s$	-	-	200	ns
t <sub>a</sub>	$I_F = 50A$ , $dI_F/dt = 100A/\mu s$	-	95	-	ns
t <sub>b</sub>	$I_F = 50A$ , $dI_F/dt = 100A/\mu s$	-	70	-	ns
Q <sub>RR</sub>	$I_F = 50A$ , $dI_F/dt = 100A/\mu s$	-	800	-	nC
СЈ	V <sub>R</sub> = 10V, I <sub>F</sub> = 0A	-	160	-	pF
$R_{ heta JC}$		-	-	0.9	°C/W

#### **DEFINITIONS**

 $V_F$  = Instantaneous forward voltage (pw = 300 $\mu$ s, D = 2%).

I<sub>R</sub> = Instantaneous reverse current.

 $t_{rr}$  = Reverse recovery time (See Figure 9), summation of  $t_a$  +  $t_b$ .

 $t_a$  = Time to reach peak reverse current (See Figure 9).

 $t_b = \text{Time from peak I}_{RM} \text{ to projected zero crossing of I}_{RM} \text{ based on a straight line from peak I}_{RM} \text{ through 25\% of I}_{RM} \text{ (See Figure 9)}.$ 

 $Q_{RR}$  = Reverse recovery charge.

C<sub>J</sub> = Junction Capacitance.

 $R_{\theta JC}$  = Thermal resistance junction to case.

pw = pulse width.

D = duty cycle.

# **Typical Performance Curves**

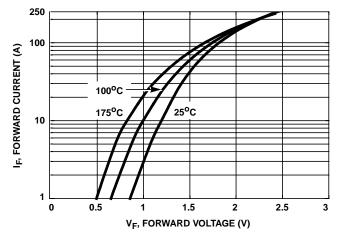


FIGURE 1. FORWARD CURRENT vs FORWARD VOLTAGE

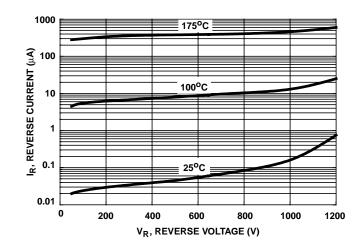


FIGURE 2. REVERSE CURRENT vs REVERSE VOLTAGE

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## Typical Performance Curves (Continued)

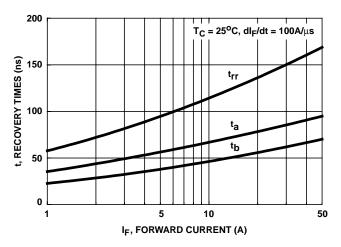


FIGURE 3.  $t_{rr}$ ,  $t_a$  AND  $t_b$  CURVES vs FORWARD CURRENT

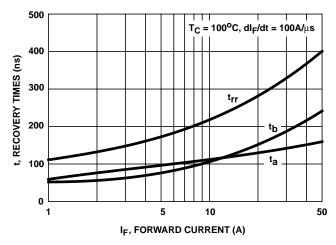


FIGURE 4.  $t_{rr}$ ,  $t_a$  and  $t_b$  curves vs forward current

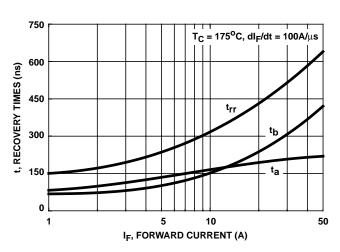


FIGURE 5.  $t_{rr}$ ,  $t_a$  AND  $t_b$  CURVES vs FORWARD CURRENT

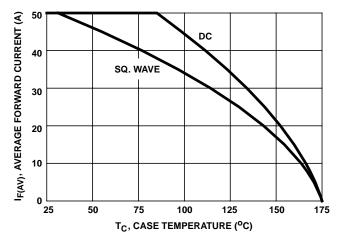


FIGURE 6. CURRENT DERATING CURVE

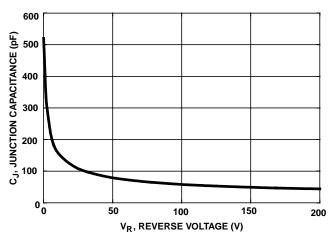


FIGURE 7. JUNCTION CAPACITANCE vs REVERSE VOLTAGE

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#### RURU50120

#### Test Circuits and Waveforms

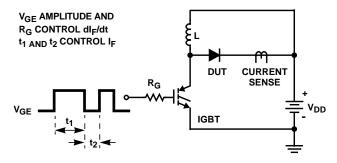


FIGURE 8. t<sub>rr</sub> TEST CIRCUIT

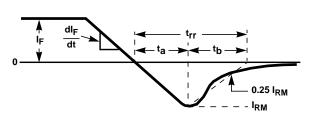


FIGURE 9. t<sub>rr</sub> WAVEFORMS AND DEFINITIONS

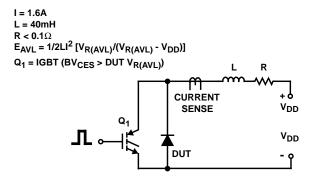


FIGURE 10. AVALANCHE ENERGY TEST CIRCUIT

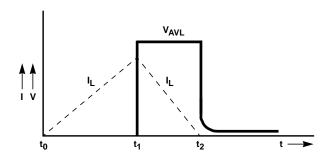


FIGURE 11. AVALANCHE CURRENT AND VOLTAGE WAVEFORMS

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